

**N&P-Channel MOSFET** 

#### **General Description**

The WSP6067 is the highest performance trench N-ch and P-ch MOSFET with extreme high cell density , which provide excellent RDSON and gate charge for most of the synchronous buck converter applications .

The WSP6067 meet the RoHS and Green Product requirement, 100% EAS guaranteed with full function reliability approved.

#### Features

- Advanced high cell density Trench technology
- Super Low Gate Charge
- Excellent CdV/dt effect decline
- 100% EAS Guaranteed
- Green Device Available

#### Absolute Maximum Ratings

### **Product Summery**

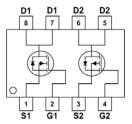
BVDSS	RDSON	ID
60V	26mΩ	6.5A
-60V	60mΩ	-4.5A

#### Applications

- High Frequency Point-of-Load Synchronous Buck Converter.
- Networking DC-DC Power System
- Load Switch

#### **SOP-8 Pin Configuration**





		Rat	ting	
Symbol	Parameter	N-Channel	P-Channel	Units
V <sub>DS</sub>	Drain-Source Voltage	60	-60	V
V <sub>GS</sub>	Gate-Source Voltage	±20	±20	V
I <sub>D</sub> @T <sub>C</sub> =25℃	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	6.5	-4.5	A
I <sub>D</sub> @T <sub>C</sub> =100℃	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	4.5	-2.8	А
I <sub>DM</sub>	Pulsed Drain Current <sup>2</sup>	24	-16	А
EAS	Single Pulse Avalanche Energy <sup>3</sup>	12	16	mJ
I <sub>AS</sub>	Avalanche Current	16	-18	A
P <sub>D</sub> @T <sub>C</sub> =25℃	Total Power Dissipation <sup>4</sup>	3.1	3.1	W
T <sub>STG</sub>	Storage Temperature Range	-55 to 150	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	-55 to 150	°C

#### **Thermal Data**

Symbol	Parameter	Тур.	Max.	Unit
R <sub>0JA</sub>	Thermal Resistance Junction-Ambient <sup>1</sup>		90	°C/W
R <sub>θJC</sub>	Thermal Resistance Junction-Case <sup>1</sup>		50	°C/W



N&P-Channel MOSFET

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =250uA	60			V
$\triangle BV_{DSS} / \triangle T_J$	BV <sub>DSS</sub> Temperature Coefficient	Reference to 25 $^\circ\!\mathrm{C}$ , I_D=1mA		0.063		V/℃
Deserve	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =10V , I <sub>D</sub> =6.5A		26	36	20
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> =4.5V , I <sub>D</sub> =3A		36	45	mΩ
V <sub>GS(th)</sub>	Gate Threshold Voltage		1	2	3	V
$ riangle V_{GS(th)}$	V <sub>GS(th)</sub> Temperature Coefficient	$V_{GS}=V_{DS}$ , $I_{D}=250$ uA		-5.24		mV/℃
1	Drain-Source Leakage Current	$V_{\text{DS}}\text{=}48\text{V}$ , $V_{\text{GS}}\text{=}0\text{V}$ , $T_{\text{J}}\text{=}25^\circ\!\mathrm{C}$			1	— uA
I <sub>DSS</sub>	Drain-Source Leakage Current	$V_{\text{DS}}\text{=}48\text{V}$ , $V_{\text{GS}}\text{=}0\text{V}$ , $T_{\text{J}}\text{=}55^\circ\!\mathrm{C}$			5	
I <sub>GSS</sub>	Gate-Source Leakage Current	$V_{GS}=\pm20V$ , $V_{DS}=0V$			±100	nA
gfs	Forward Transconductance	V <sub>DS</sub> =5V , I <sub>D</sub> =8A		21		S
R <sub>g</sub>	Gate Resistance	V <sub>DS</sub> =0V , V <sub>GS</sub> =0V , f=1MHz		3.0	4.5	Ω
Qg	Total Gate Charge (4.5V)			14	20	
Q <sub>gs</sub>	Gate-Source Charge	$V_{DS}$ =48V , $V_{GS}$ =4.5V , $I_{D}$ =6.5A		2.6		nC
Q <sub>gd</sub>	Gate-Drain Charge			2.2		
T <sub>d(on)</sub>	Turn-On Delay Time			8		
Tr	Rise Time	$V_{DD}$ =30V , $V_{GS}$ =10V , $R_{G}$ =6 $\Omega$ ,		6		
T <sub>d(off)</sub>	Turn-Off Delay Time	I <sub>D</sub> =1A ,RL=6Ω		23		ns
T <sub>f</sub>	Fall Time			6		
C <sub>iss</sub>	Input Capacitance			670		
Coss	Output Capacitance	V <sub>DS</sub> =15V , V <sub>GS</sub> =0V , f=1MHz		70		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			35		

### N-Channel Electrical Characteristics (TJ=25 °C, unless otherwise noted)

### **Guaranteed Avalanche Characteristics**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
EAS	Single Pulse Avalanche Energy <sup>5</sup>	V <sub>DD</sub> =25V , L=0.1mH , I <sub>AS</sub> =16A	11.2			mJ

#### **Diode Characteristics**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Is	Continuous Source Current <sup>1,6</sup>	$V_G = V_D = 0V$ , Force Current			2.5	А
I <sub>SM</sub>	Pulsed Source Current <sup>2,6</sup>				24	А
V <sub>SD</sub>	Diode Forward Voltage <sup>2</sup>	V <sub>GS</sub> =0V , I <sub>S</sub> =1.7A,T <sub>J</sub> =25℃			1.1	V

Note :

1. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper,t<10sec.

2.The data tested by pulsed , pulse width  $\leq$  300us , duty cycle  $\leq$  2%

3. The EAS data shows Max. rating . The test condition is  $V_{DD}=25V$ ,  $V_{GS}=10V$ , L=0.1 mH,  $I_{AS}=16A$ 

4. The power dissipation is limited by 150°C junction temperature

5. The Min. value is 100% EAS tested guarantee.

6.The data is theoretically the same as  $I_D$  and  $I_{DM}$ , in real applications , should be limited by total power dissipation.



**N&P-Channel MOSFET** 

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =-250uA	-60			V
$\triangle BV_{DSS} / \triangle T_J$	BV <sub>DSS</sub> Temperature Coefficient	Reference to 25 $^\circ\!\mathrm{C}$ , I_D=-1mA		-0.03		V/℃
Deserve	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =-10V , I <sub>D</sub> =-4.5A		60	75	<b>m</b> ()
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> =-4.5V , I <sub>D</sub> =-1A		75	85	mΩ
V <sub>GS(th)</sub>	Gate Threshold Voltage		-1.5	-2.0	-2.5	V
$ riangle V_{GS(th)}$	V <sub>GS(th)</sub> Temperature Coefficient	—V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =-250uA		4.56		mV/℃
	Drain-Source Leakage Current	$V_{DS}$ =-48V , $V_{GS}$ =0V , TJ=25 $^\circ C$			1	— uA
I <sub>DSS</sub>	Dialit-Source Leakage Current	$V_{DS}$ =-48V , $V_{GS}$ =0V , TJ=55 $^\circ C$			5	
I <sub>GSS</sub>	Gate-Source Leakage Current	$V_{GS}$ = $\pm20V$ , $V_{DS}$ = $0V$			±100	nA
gfs	Forward Transconductance	V <sub>DS</sub> =-5V , I <sub>D</sub> =-4.5A		18		S
Rg	Gate Resistance	V <sub>DS</sub> =0V , V <sub>GS</sub> =0V , f=1MHz		1.5	2.7	Ω
Qg	Total Gate Charge (-4.5V)			12		
Q <sub>gs</sub>	Gate-Source Charge	V <sub>DS</sub> =-48V , V <sub>GS</sub> =-10V , I <sub>D</sub> =-4.5A		1.5		nC
Q <sub>gd</sub>	Gate-Drain Charge			3.0		
T <sub>d(on)</sub>	Turn-On Delay Time			7.5		
Tr	Rise Time	$V_{DD}$ =-30V , $V_{GS}$ =-10V , $R_{G}$ =6 $\Omega$ ,		4.5		
T <sub>d(off)</sub>	Turn-Off Delay Time	I <sub>D</sub> =-1A,R∟=30Ω.		38		ns
T <sub>f</sub>	Fall Time			28		
C <sub>iss</sub>	Input Capacitance			500		
Coss	Output Capacitance	V <sub>DS</sub> =-15V , V <sub>GS</sub> =0V , f=1MHz		66		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			32		

### P-Channel Electrical Characteristics (T\_J=25 $\,\,{}^\circ\!\!\!\!\!^\circ$ , unless otherwise noted)

#### **Guaranteed Avalanche Characteristics**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
EAS	Single Pulse Avalanche Energy $^5$	V <sub>DD</sub> =-25V , L=0.1mH , I <sub>AS</sub> =-18A	11			mJ

#### **Diode Characteristics**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
ls	Continuous Source Current <sup>1,6</sup>	$V_{G}=V_{D}=0V$ , Force Current			-1	А
I <sub>SM</sub>	Pulsed Source Current <sup>2,6</sup>				-18	A
V <sub>SD</sub>	Diode Forward Voltage <sup>2</sup>	$V_{GS}$ =0V , $I_{S}$ =-1A , $T_{J}$ =25 $^{\circ}$ C			-1.1	V

Note :

2.The data tested by pulsed , pulse width  $\,\leq\,$  300us , duty cycle  $\,\leq\,$  2%

3. The EAS data shows Max. rating . The test condition is  $V_{DD}$ =-25V,  $V_{GS}$ =-10V, L=0.1mH, I<sub>AS</sub>=-18A

5. The Min. value is 100% EAS tested guarantee.

6.The data is theoretically the same as  $I_D$  and  $I_{DM}$ , in real applications , should be limited by total power dissipation.

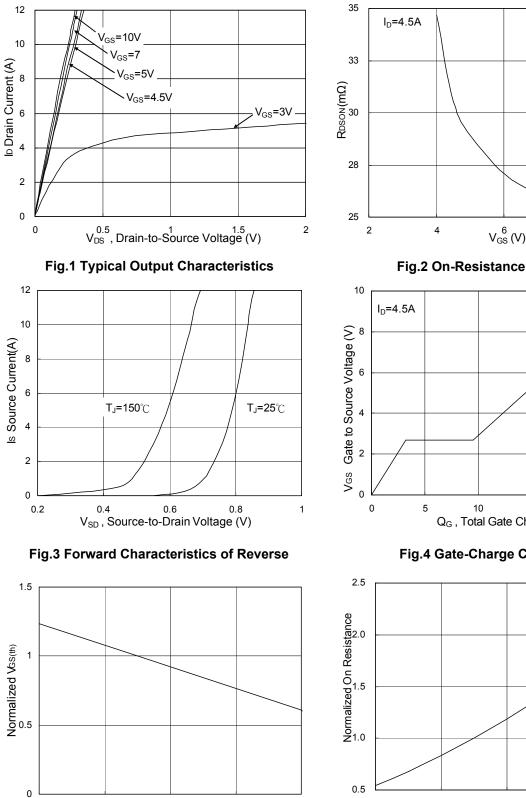
<sup>1.</sup> The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper,t<10 sec.

<sup>4.</sup>The power dissipation is limited by 150  $^\circ\!\!\mathbb{C}$  junction temperature



#### **N&P-Channel MOSFET**

### **N-Channel Typical Characteristics**





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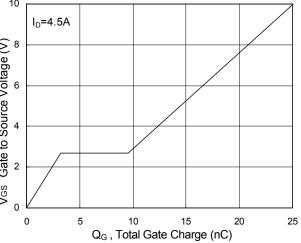
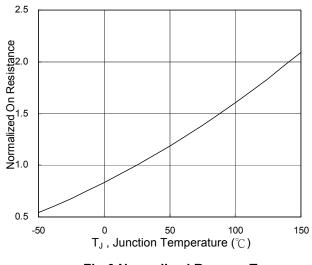


Fig.4 Gate-Charge Characteristics



#### Fig.6 Normalized R<sub>DSON</sub> v.s T<sub>J</sub>

 $T_{\text{J}}$  , Junction Temperature (°C )  $^{100}$ 

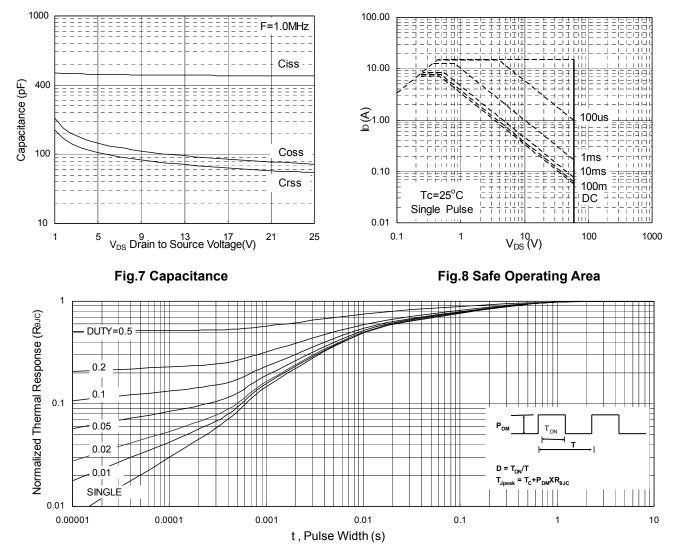
Fig.5 Normalized  $V_{GS(th)}$  v.s T<sub>J</sub>

-50

150



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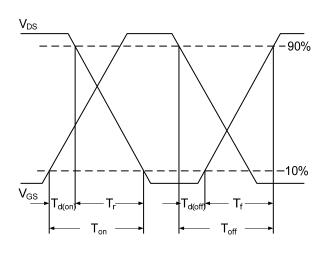


Fig.10 Switching Time Waveform

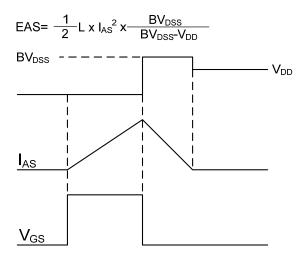
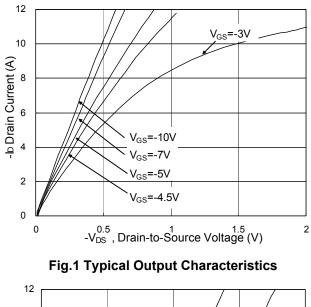


Fig.11 Unclamped Inductive Waveform



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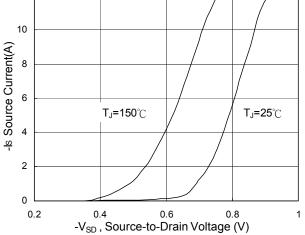
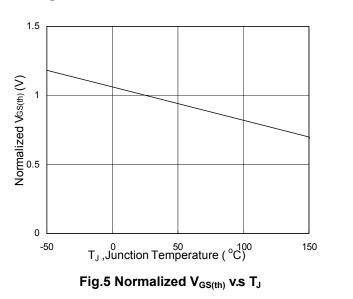


Fig.3 Forward Characteristics of Reverse



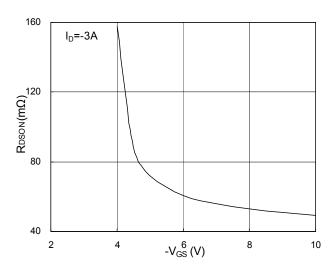


Fig.2 On-Resistance v.s Gate-Source

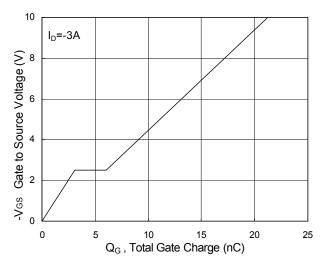


Fig.4 Gate-Charge Characteristics

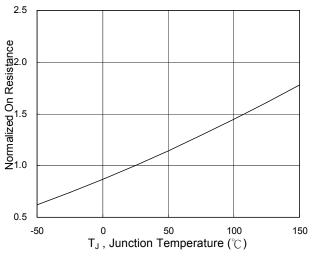
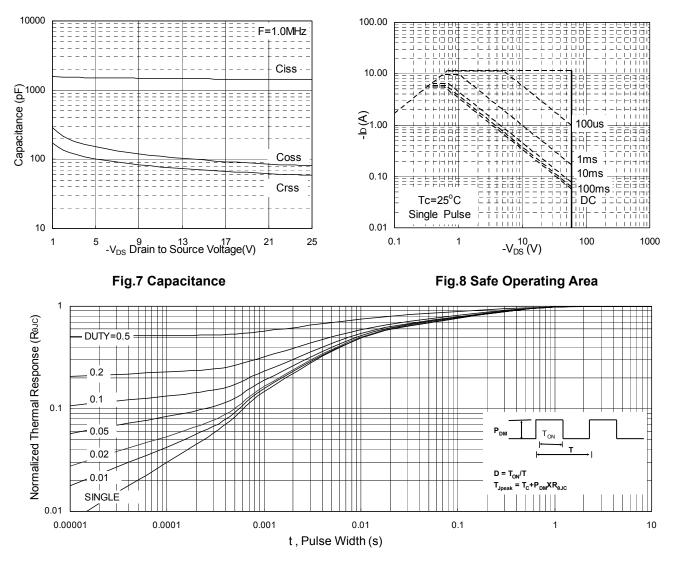


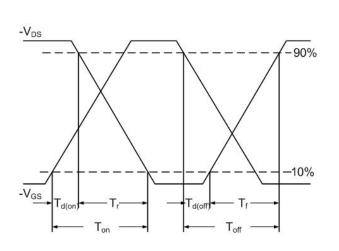
Fig.6 Normalized R<sub>DSON</sub> v.s T<sub>J</sub>



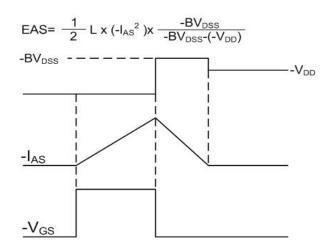
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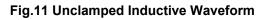














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